ABTS-Li

Advanced Burn-In & Test System

Cost-effective, reliable and highly configurable system engineered for burn-in and test of high power devices using sockets with independent thermal control



System Benefits:

- Addresses High Power Burn-In
 - Burn-in and test of high-power logic devices up to 75W
 - Fully integrated individual device temperature sensing, control, and reporting
 - Individual power supplies per DUT prevents burned sockets & BIBs caused by shorted devices
- High Reliability and Uptime
 - Redundant architecture
 - Hot-swap power supplies
- Low Cost of Ownership
 - Up to 56 burn-in board slots
 - 28 pattern zones
 - Small footprint
 - No side access required
 - Highly efficient power delivery
 - Low-power standby mode
- Highly Configurable for Production and Engineering

"Setting the Test Standard for Tomorrow"

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